Thermomechanical Fatigue of Solder Interconnects in Automotive Electronics

 $\Delta T = -40$ to $125^{\circ}C$

- $\Delta\sigma$ due to CTE mismatch
- permanent deformation of solder by diffusional creep
- formation of vacancies at grain boundaries
- growth of vacancies into microcracks or voids
- fatigue crack initiation and propagation



Liu and Pao, J. Electr. Mater., 26 [9] 1058-1064 (1997)

AME 60646: Failure of Materials (R.K. Roeder) =

Thermomechanical Fatigue of Solder Interconnects in Automotive Electronics

Accelerated laboratory tests simultaneously cycle T and four point bending strain on the circuit board

 $\Delta T = -50 \text{ to } 150^{\circ}\text{C}$ $\Delta \varepsilon = \pm 1000 \ \mu \varepsilon$





Torres-Montoya and Mason, 2003

AME 60646: Failure of Materials (R.K. Roeder) =